

Features

- Single Supply Voltage, Range 2.7V to 3.6V
- Single Supply for Read and Write
- Software Protected Programming
- Fast Read Access Time - 250 ns
- Low Power Dissipation
 - 15 mA Active Current
 - 20 μ A CMOS Standby Current
- Sector Program Operation
 - Single Cycle Reprogram (Erase and Program)
 - 1024 Sectors (256 bytes/sector)
 - Internal Address and Data Latches for 256-Bytes
- Two 8 KB Boot Blocks with Lockout
- Fast Sector Program Cycle Time - 20 ms Max.
- Internal Program Control and Timer
- DATA Polling for End of Program Detection
- Typical Endurance > 10,000 Cycles
- CMOS and TTL Compatible Inputs and Outputs
- Commercial and Industrial Temperature Ranges

Description

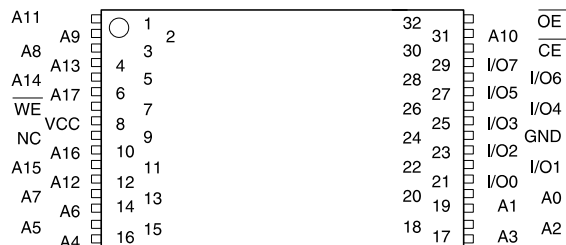
The AT29BV020 is a 2.7-volt-only in-system Flash Programmable and Erasable Read Only Memory (PEROM). Its 2 megabits of memory is organized as 262,144 words by 8 bits. Manufactured with Atmel's advanced nonvolatile CMOS EEPROM technology, the device offers access times up to 250 ns, and a low 54 mW power dissipation. When the device is deselected, the CMOS standby current is less than 20 μ A. The device endurance is such that any sector can typically be written to in excess of 10,000 times. The programming algorithm is compatible with other devices in Atmel's Low Voltage Flash family of products.

(continued)

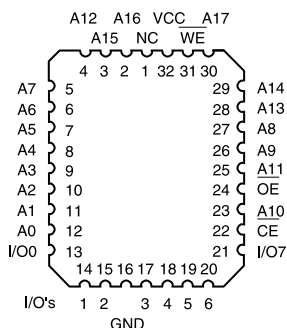
Pin Configurations

| Pin | Name | Function |
|-----------------|------|---------------------|
| A0 - A17 | | Addresses |
| \overline{CE} | | Chip Enable |
| \overline{OE} | | Output Enable |
| \overline{WE} | | Write Enable |
| I/O0 - I/O7 | | Data Inputs/Outputs |
| NC | | No Connect |

TSOP Top View
Type 1



PLCC Top View



0402B

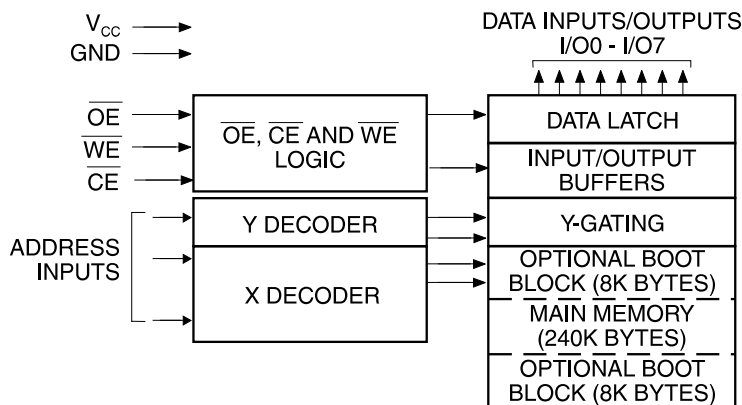


Description (Continued)

To allow for simple in-system reprogrammability, the AT29BV020 does not require high input voltages for programming. The device can be operated with a single 2.7V to 3.6V supply. Reading data out of the device is similar to reading from an EPROM. Reprogramming the AT29BV020 is performed on a sector basis; 256-bytes of data are loaded into the device and then simultaneously programmed.

During a reprogram cycle, the address locations and 256-bytes of data are captured at microprocessor speed and internally latched, freeing the address and data bus for other operations. Following the initiation of a program cycle, the device will automatically erase the sector and then program the latched data using an internal control timer. The end of a program cycle can be detected by DATA polling of I/O7. Once the end of a program cycle has been detected, a new access for a read or program can begin.

Block Diagram



Device Operation

READ: The AT29BV020 is accessed like an EPROM. When CE and OE are low and WE is high, the data stored at the memory location determined by the address pins is asserted on the outputs. The outputs are put in the high impedance state whenever CE or OE is high. This dual-line control gives designers flexibility in preventing bus contention.

SOFTWARE DATA PROTECTION PROGRAMMING: The AT29BV020 has 1024 individual sectors, each 256-bytes. Using the software data protection feature, byte loads are used to enter the 256-bytes of a sector to be programmed. The AT29BV020 can only be programmed or reprogrammed using the software data protection feature. The device is programmed on a sector basis. If a byte of data within the sector is to be changed, data for the entire 256-byte sector must be loaded into the device. The data in any byte that is not loaded during the programming of its sector will be indeterminate. The AT29BV020 automatically does a sector erase prior to loading the data into the sector. An erase command is not required.

Software data protection protects the device from inadvertent programming. A series of three program commands to specific addresses with specific data must be presented to the device before programming may occur. The same three program commands must begin each program operation. All software program commands must obey the sector program timing specifications. Power transitions

will not reset the software data protection feature, however the software feature will guard against inadvertent program cycles during power transitions.

Any attempt to write to the device without the 3-byte command sequence will start the internal write timers. No data will be written to the device; however, for the duration of t_{wc}, a read operation will effectively be a polling operation.

After the software data protection's 3-byte command code is given, a byte load is performed by applying a low pulse on the \overline{WE} or CE input with CE or WE low (respectively) and OE high. The address is latched on the falling edge of CE or WE, whichever occurs last. The data is latched by the first rising edge of CE or WE.

The 256-bytes of data must be loaded into each sector. Any byte that is not loaded during the programming of its sector will be indeterminate. Once the bytes of a sector are loaded into the device, they are simultaneously programmed during the internal programming period. After the first data byte has been loaded into the device, successive bytes are entered in the same manner. Each new byte to be programmed must have its high to low transition on WE (or CE) within 150 μ s of the low to high transition of WE (or CE) of the preceding byte. If a high to low transition is not detected within 150 μ s of the last low to high transition, the load period will end and the internal programming period will start. A8 to A17 specify the sector address. The

(continued)

Device Operation (Continued)

sector address must be valid during each high to low transition of \overline{WE} (or \overline{CE}). A0 to A7 specify the byte address within the sector. The bytes may be loaded in any order; sequential loading is not required.

HARDWARE DATA PROTECTION: Hardware features protect against inadvertent programs to the AT29BV020 in the following ways: (a) V_{CC} sense— if V_{CC} is below 2.0V (typical), the program function is inhibited. (b) V_{CC} power on delay— once V_{CC} has reached the V_{CC} sense level, the device will automatically time out 10 ms (typical) before programming. (c) Program inhibit— holding any one of \overline{OE} low, \overline{CE} high or \overline{WE} high inhibits program cycles. (d) Noise filter— pulses of less than 15 ns (typical) on the \overline{WE} or \overline{CE} inputs will not initiate a program cycle.

INPUT LEVELS: While operating with a 2.7V to 3.6V power supply, the address inputs and control inputs (\overline{OE} , \overline{CE} and \overline{WE}) may be driven from 0 to 5.5V without adversely affecting the operation of the device. The I/O lines can only be driven from 0 to $V_{CC} + 0.6V$.

PRODUCT IDENTIFICATION: The product identification mode identifies the device and manufacturer as Atmel. It may be accessed by hardware or software operation. The hardware operation mode can be used by an external programmer to identify the correct programming algorithm for the Atmel product. In addition, users may wish to use the software product identification mode to identify the part (i.e. using the device code), and have the system software use the appropriate sector size for program operations. In this manner, the user can have a common board design for 256K to 4-megabit densities and, with each density's sector size in a memory map, have the system software apply the appropriate sector size.

For details, see Operating Modes (for hardware operation) or Software Product Identification. The manufacturer and device code is the same for both methods of identification.

Absolute Maximum Ratings*

Temperature Under Bias..... -55°C to +125°C

Storage Temperature..... -65°C to +150°C

All Input Voltages
(including NC Pins)
with Respect to Ground -0.6V to +6.25V

All Output Voltages
with Respect to Ground -0.6V to $V_{CC} + 0.6V$

Voltage on A9
(including NC Pins)
with Respect to Ground -0.6V to +13.5V

DATA POLLING: The AT29BV020 features \overline{DATA} polling to indicate the end of a program cycle. During a program cycle an attempted read of the last byte loaded will result in the complement of the loaded data on I/O7. Once the program cycle has been completed, true \overline{data} is valid on all outputs and the next cycle may begin. \overline{DATA} polling may begin at any time during the program cycle.

TOGGLE BIT: In addition to \overline{DATA} polling the AT29BV020 provides another method for determining the end of a program or erase cycle. During a program or erase operation, successive attempts to read data from the device will result in I/O6 toggling between one and zero. Once the program cycle has completed, I/O6 will stop toggling and valid data will be read. Examining the toggle bit may begin at any time during a program cycle.

OPTIONAL CHIP ERASE MODES: The entire device may be erased by using a 6-byte software code. Please see Software Chip Erase application note for details.

BOOT BLOCK PROGRAMMING LOCKOUT: The AT29BV020 has two designated memory blocks that have a programming lockout feature. This feature prevents programming of data in the designated block once the feature has been enabled. Each of these blocks consists of 8K bytes; the programming lockout feature can be set independently for either block. While the lockout feature does not have to be activated, it can be activated for either or both blocks.

These two 8K memory sections are referred to as *boot blocks*. Secure code which will bring up a system can be contained in a boot block. The AT29BV020 blocks are located in the first 8K bytes of memory and the last 8K bytes of memory. The boot block programming lockout feature can therefore support systems that boot from the lower addresses of memory or the higher addresses. Once the programming lockout feature has been activated, the data in that block can no longer be erased or programmed; data in other memory locations can still be changed through the regular programming methods. To activate the lockout feature, a series of seven program commands to specific addresses with specific data must be performed. Please see Boot Block Lockout Feature Enable Algorithm.

If the boot block lockout feature has been activated on either block, the chip erase function will be disabled.

(continued)

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Device Operation (Continued)

BOOT BLOCK LOCKOUT DETECTION: A software method is available to determine whether programming of either boot block section is locked out. See Software Product Identification Entry and Exit sections. When the device is in the software product identification mode, a read from location 00002H will show if programming the lower address boot block is locked out while reading location

FFFF2H will do so for the upper boot block. If the data is FE, the corresponding block can be programmed; if the data is FF, the program lockout feature has been activated and the corresponding block cannot be programmed. The software product identification exit mode should be used to return to standard operation.

DC and AC Operating Range

| | | AT29BV020-25 | AT29BV020-35 |
|---------------------------------|------|--------------|--------------|
| Operating Temperature (Case) | Com. | 0°C - 70°C | 0°C - 70°C |
| | Ind. | -40°C - 85°C | -40°C - 85°C |
| VCC Power Supply ⁽¹⁾ | | 2.7V to 3.6V | 2.7V to 3.6V |

1. After power is applied and VCC is at the minimum specified data sheet value, the system should wait 20 ms before an operational mode is started.

Operating Modes

| Mode | \overline{CE} | \overline{OE} | \overline{WE} | Ai | I/O |
|-------------------------|-----------------|------------------|-----------------|---|----------------------------------|
| Read | V _{IL} | V _{IL} | V _{IH} | Ai | D _{OUT} |
| Program ⁽²⁾ | V _{IL} | V _{IH} | V _{IL} | Ai | D _{IN} |
| Standby/Write Inhibit | V _{IH} | X ⁽¹⁾ | X | X | High Z |
| Program Inhibit | X | X | V _{IH} | | |
| Program Inhibit | X | V _{IL} | X | | |
| Output Disable | X | V _{IH} | X | | High Z |
| Product Identification | | | | | |
| Hardware | V _{IL} | V _{IL} | V _{IH} | A1 - A17 = V _{IL} , A9 = V _H ⁽³⁾ , A0 = V _{IL} | Manufacturer Code ⁽⁴⁾ |
| | | | | A1 - A17 = V _{IL} , A9 = V _H ⁽³⁾ , A0 = V _{IH} | Device Code ⁽⁴⁾ |
| Software ⁽⁵⁾ | | | | A0 = V _{IL} , A1 - A17 = V _{IL} | Manufacturer Code ⁽⁴⁾ |
| | | | | A0 = V _{IH} , A1 - A17 = V _{IL} | Device Code ⁽⁴⁾ |

Notes: 1. X can be V_{IL} or V_{IH}.

2. Refer to AC Programming Waveforms.

3. V_H = 12.0V ± 0.5V.

4. Manufacturer Code is 1F. The Device Code is BA.

5. See details under Software Product Identification Entry/Exit.

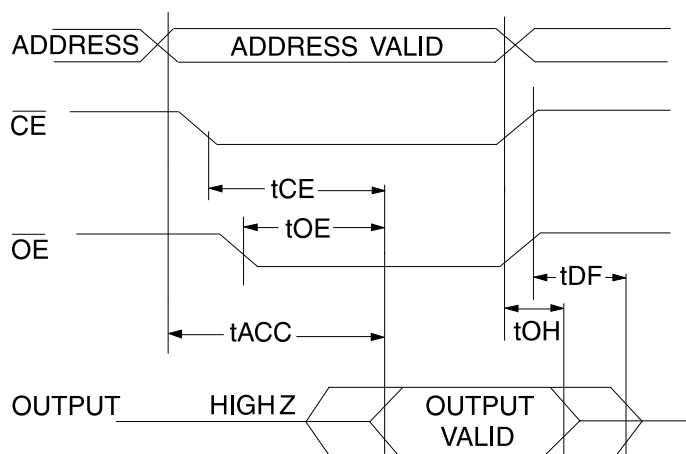
DC Characteristics

| Symbol | Parameter | Condition | Min | Max | Units |
|------------------|--------------------------|---|------|------|-------|
| I _{LI} | Input Load Current | V _{IN} = 0V to V _{CC} | | 1 | μA |
| I _{LO} | Output Leakage Current | V _{I/O} = 0V to V _{CC} | | 1 | μA |
| I _{SB1} | VCC Standby Current CMOS | \overline{CE} = V _{CC} - 0.3V to V _{CC} | Com. | 20 | μA |
| | | | Ind. | 50 | μA |
| I _{SB2} | VCC Standby Current TTL | \overline{CE} = 2.0V to V _{CC} | | 1 | mA |
| I _{CC} | VCC Active Current | f = 5 MHz; I _{OUT} = 0 mA; V _{CC} = 3.6V | | 15 | mA |
| V _{IL} | Input Low Voltage | | | 0.6 | V |
| V _{IH} | Input High Voltage | | 2.0 | | V |
| V _{OL} | Output Low Voltage | I _{OL} = 1.6 mA; V _{CC} = 3.0V | | 0.45 | V |
| V _{OH} | Output High Voltage | I _{OH} = -100 μA; V _{CC} = 3.0V | 2.4 | | V |

AC Read Characteristics

| Symbol | Parameter | AT29BV020-25 | | AT29BV020-35 | | Units |
|------------------|---|--------------|-----|--------------|-----|-------|
| | | Min | Max | Min | Max | |
| t_{ACC} | Address to Output Delay | | 250 | | 350 | ns |
| $t_{CE}^{(1)}$ | \overline{CE} to Output Delay | | 250 | | 350 | ns |
| $t_{OE}^{(2)}$ | \overline{OE} to Output Delay | 0 | 120 | 0 | 150 | ns |
| $t_{DF}^{(3,4)}$ | \overline{CE} or \overline{OE} to Output Float | 0 | 60 | 0 | 75 | ns |
| t_{OH} | Output Hold from \overline{OE} , \overline{CE} or Address, whichever occurred first | 0 | | 0 | | ns |

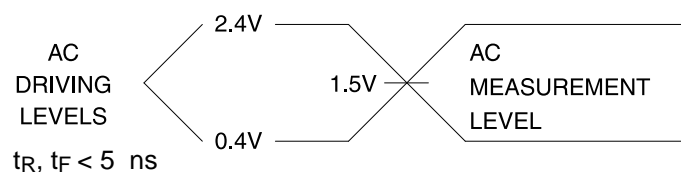
AC Read Waveforms



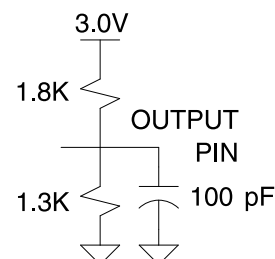
Notes: 1. \overline{CE} may be delayed up to $t_{ACC} - t_{CE}$ after the address transition without impact on t_{ACC} .
 2. \overline{OE} may be delayed up to $t_{CE} - t_{OE}$ after the falling edge of \overline{CE} without impact on t_{CE} or by $t_{ACC} - t_{OE}$ after an address change without impact on t_{ACC} .

3. t_{DF} is specified from \overline{OE} or \overline{CE} whichever occurs first ($C_L = 5$ pF).
 4. This parameter is characterized and is not 100% tested.

Input Test Waveforms and Measurement Level



Output Test Load



Pin Capacitance ($f = 1$ MHz, $T = 25^\circ\text{C}$)⁽¹⁾

| | Typ | Max | Units | Conditions |
|-----------|-----|-----|-------|----------------|
| C_{IN} | 4 | 6 | pF | $V_{IN} = 0V$ |
| C_{OUT} | 8 | 12 | pF | $V_{OUT} = 0V$ |

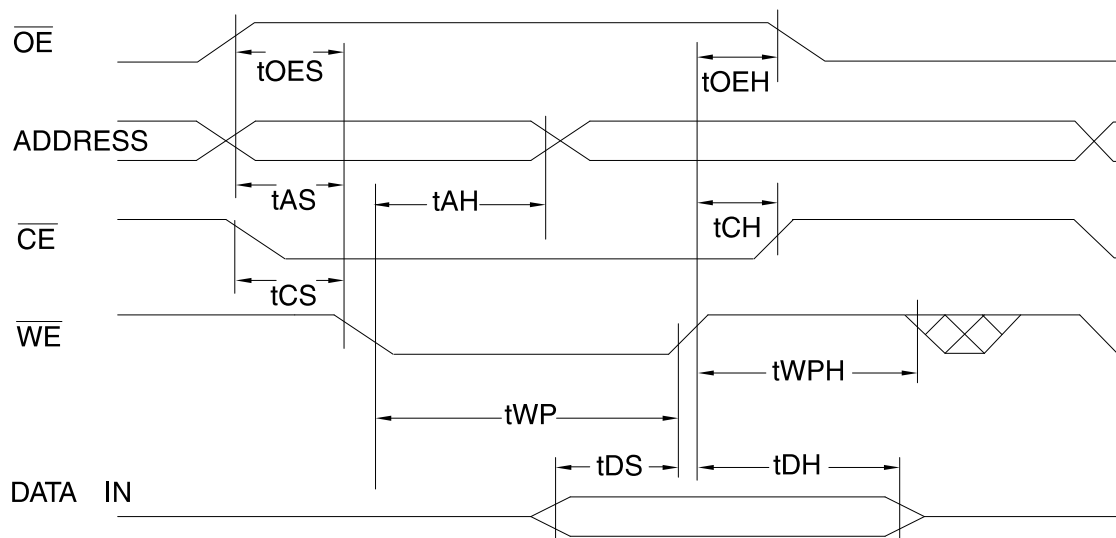
Note: 1. These parameters are characterized and not 100% tested.

AC Byte Load Characteristics

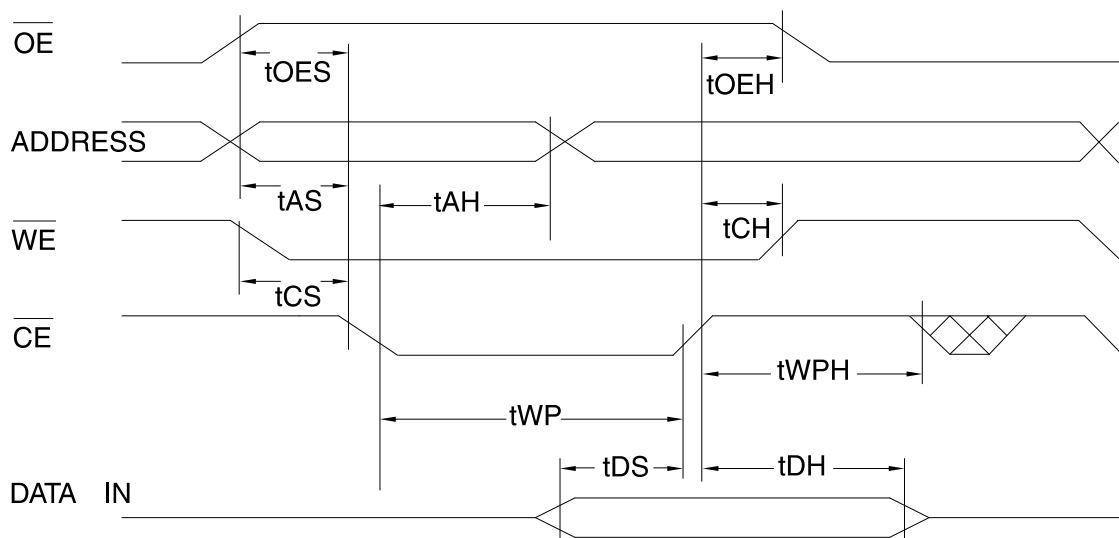
| Symbol | Parameter | Min | Max | Units |
|-------------------|--|-----|-----|-------|
| t_{AS}, t_{OES} | Address, \overline{OE} Set-up Time | 10 | | ns |
| t_{AH} | Address Hold Time | 100 | | ns |
| t_{CS} | Chip Select Set-up Time | 0 | | ns |
| t_{CH} | Chip Select Hold Time | 0 | | ns |
| t_{WP} | Write Pulse Width (\overline{WE} or \overline{CE}) | 200 | | ns |
| t_{DS} | Data Set-up Time | 100 | | ns |
| t_{DH}, t_{OEH} | Data, \overline{OE} Hold Time | 10 | | ns |
| t_{WPH} | Write Pulse Width High | 200 | | ns |

AC Byte Load Waveforms ^(1, 2)

\overline{WE} Controlled



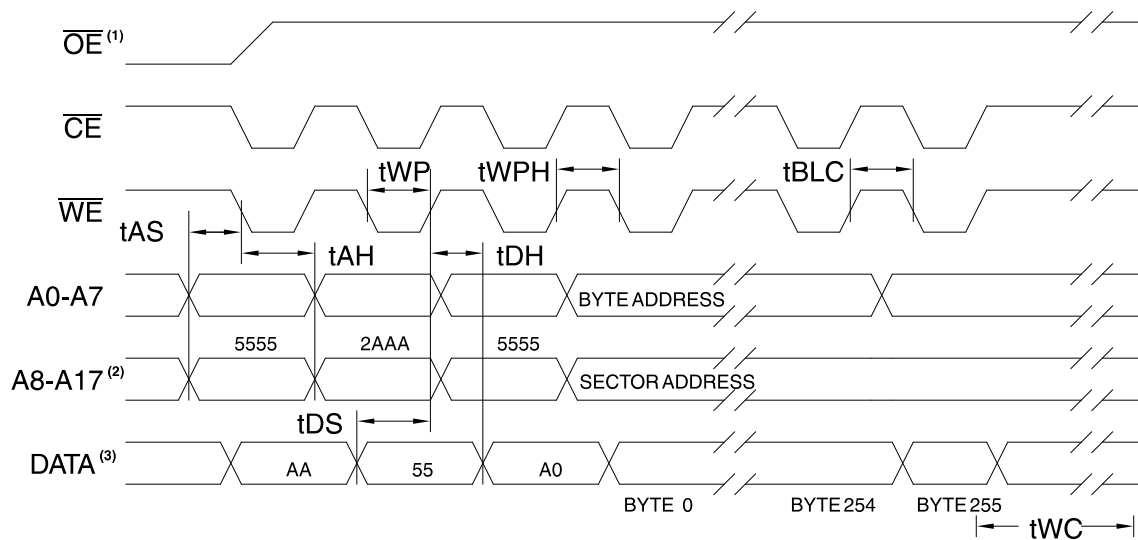
\overline{CE} Controlled



Program Cycle Characteristics

| Symbol | Parameter | Min | Max | Units |
|------------------|------------------------|-----|-----|-------|
| t _{WC} | Write Cycle Time | | 20 | ms |
| t _{AS} | Address Set-up Time | 10 | | ns |
| t _{AH} | Address Hold Time | 100 | | ns |
| t _{DS} | Data Set-up Time | 100 | | ns |
| t _{DH} | Data Hold Time | 10 | | ns |
| t _{WP} | Write Pulse Width | 200 | | ns |
| t _{BLC} | Byte Load Cycle Time | | 150 | μs |
| t _{WPH} | Write Pulse Width High | 200 | | ns |

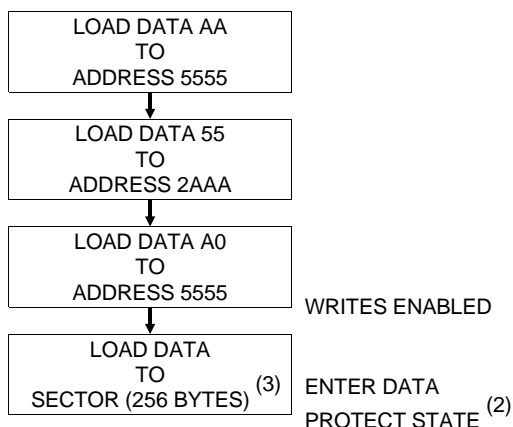
Software Protected Program Waveform



- Notes:
1. \overline{OE} must be high when \overline{WE} and \overline{CE} are both low.
 2. A8 through A17 must specify the sector address during each high to low transition of \overline{WE} (or \overline{CE}) after the software code has been entered.

3. Data in bytes not loaded within a sector being programmed may be altered by the program operation; therefore, all bytes within a sector must be loaded.

Programming Algorithm ⁽¹⁾



Notes for software program code:

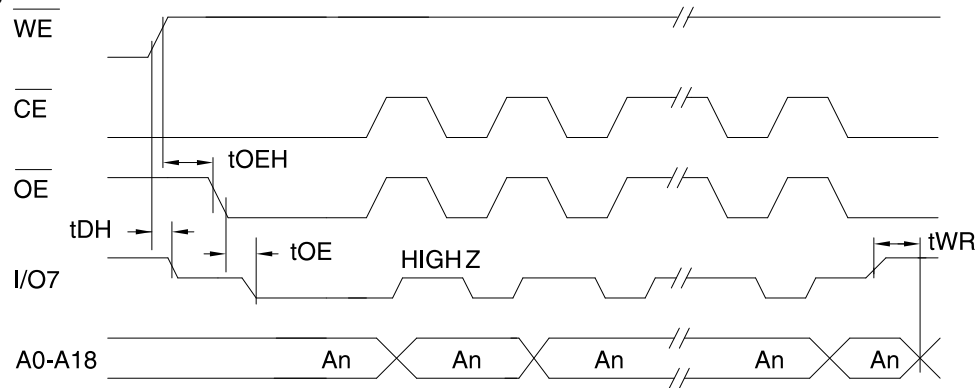
1. Data Format: I/O7 - I/O0 (Hex); Address Format: A14 - A0 (Hex).
2. Data Protect state will be re-activated at end of program cycle.
3. 256-bytes of data **MUST BE** loaded.

Data Polling Characteristics ^(1, 2)

| Symbol | Parameter | Min | Typ | Max | Units |
|-----------------|---|-----|-----|-----|-------|
| t _{DH} | Data Hold Time | 10 | | | ns |
| t _{OE} | $\overline{\text{OE}}$ Hold Time | 10 | | | ns |
| t _{OE} | $\overline{\text{OE}}$ to Output Delay ⁽²⁾ | | | | ns |
| t _{WR} | Write Recovery Time | 0 | | | ns |

Notes: 1. These parameters are characterized and not 100% tested.
2. See t_{OE} spec in AC Read Characteristics.

Data Polling Waveforms

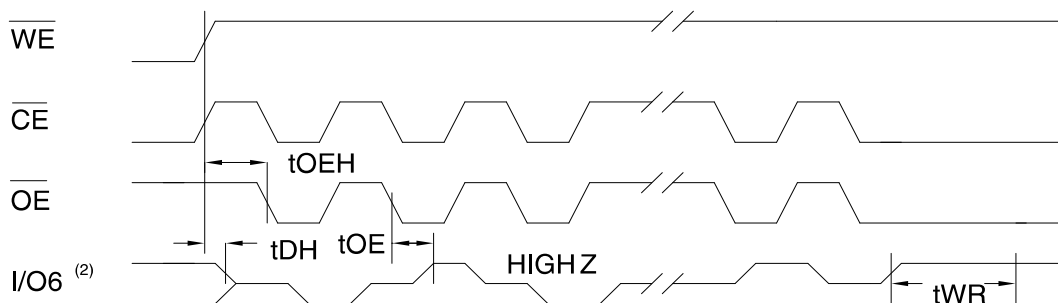


Toggle Bit Characteristics ⁽¹⁾

| Symbol | Parameter | Min | Typ | Max | Units |
|-------------------|---|-----|-----|-----|-------|
| t _{DH} | Data Hold Time | 10 | | | ns |
| t _{OE} | $\overline{\text{OE}}$ Hold Time | 10 | | | ns |
| t _{OE} | $\overline{\text{OE}}$ to Output Delay ⁽²⁾ | | | | ns |
| t _{OEHP} | $\overline{\text{OE}}$ High Pulse | 150 | | | ns |
| t _{WR} | Write Recovery Time | 0 | | | ns |

Notes: 1. These parameters are characterized and not 100% tested.
2. See t_{OE} spec in AC Read Characteristics.

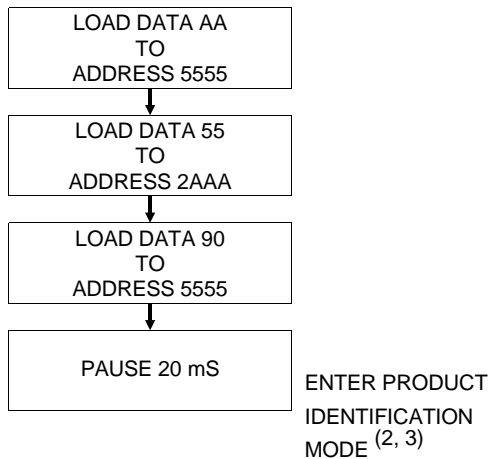
Toggle Bit Waveforms ^(1, 3)



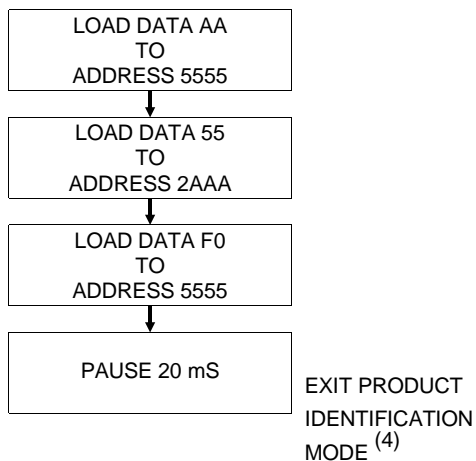
Notes: 1. Toggling either $\overline{\text{OE}}$ or $\overline{\text{CE}}$ or both $\overline{\text{OE}}$ and $\overline{\text{CE}}$ will operate toggle bit.

2. Beginning and ending state of I/O6 will vary.
3. Any address location may be used but the address should not vary.

Software Product Identification Entry ⁽¹⁾



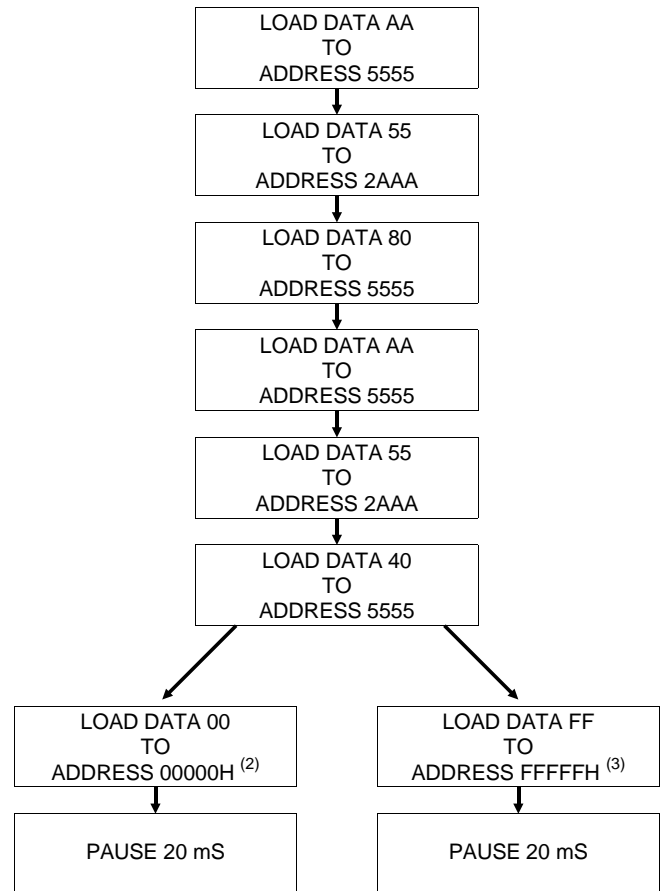
Software Product Identification Exit ⁽¹⁾



Notes for software product identification:

1. Data Format: I/O7 - I/O0 (Hex);
Address Format: A14 - A0 (Hex).
2. A1 - A17 = V_{IL}.
Manufacturer Code is read for A0 = V_{IL};
Device Code is read for A0 = V_{IH}.
3. The device does not remain in identification mode if powered down.
4. The device returns to standard operation mode.
5. Manufacturer Code is 1F. The Device Code is BA.

Boot Block Lockout Feature Enable Algorithm ⁽¹⁾



Notes for boot block lockout feature enable:

1. Data Format: I/O7 - I/O0 (Hex);
Address Format: A14 - A0 (Hex).
2. Lockout feature set on lower address boot block.
3. Lockout feature set on higher address boot block.



Ordering Information

| t _{ACC} (ns) | I _{CC} (mA) | | Ordering Code | Package | Operation Range |
|--------------------------|----------------------|---------|----------------------------------|------------|------------------------------|
| | Active | Standby | | | |
| 250 | 15 | 0.02 | AT29BV020-25JC AT29BV020-25TC | 32J 32T | Commercial (0° to 70°C) |
| | 15 | 0.05 | AT29BV020-25JI AT29BV020-25TI | 32J 32T | Industrial (-40° to 85°C) |
| 350 | 15 | 0.02 | AT29BV020-35JC AT29BV020-35TC | 32J 32T | Commercial (0° to 70°C) |
| | 15 | 0.05 | AT29BV020-35JI AT29BV020-35TI | 32J 32T | Industrial (-40° to 85°C) |

| Package Type | |
|--------------|---|
| 32J | 32 Lead, Plastic J-Leaded Chip Carrier (PLCC) |
| 32T | 32 Lead, Thin Small Outline Package (TSOP) |